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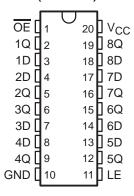
- **EPIC™** (Enhanced-Performance Implanted **CMOS) Process**
- Inputs Are TTL-Voltage Compatible
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- **ESD Protection Exceeds 2000 V Per** MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

### description

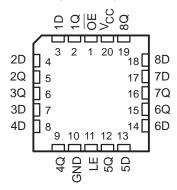
The 'AHCT373 devices are octal-transparent D-type latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is low, the Q outputs are latched at the logic levels of the D inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

SN54AHCT373 . . . J OR W PACKAGE SN74AHCT373...DB, DGV, DW, N, OR PW PACKAGE (TOP VIEW)



SN54AHCT373 . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{\sf OE}$  should be tied to  ${\sf V}_{\sf CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHCT373 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AHCT373 is characterized for operation from -40°C to 85°C.

#### **FUNCTION TABLE** (each latch)

	INPUTS		OUTPUT
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q <sub>0</sub>
н	X	X	Z



testing of all parameters

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

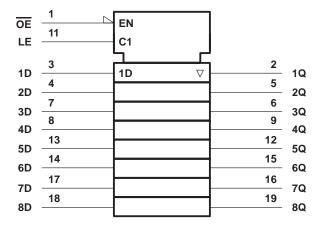
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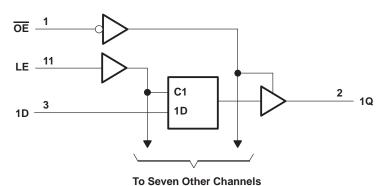
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### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
	0.5 V to 7 V
Output voltage range, VO (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}(V_I < 0)$	–20 mA
Output clamp current, IOK (VO < 0 or VO > VCO	c) ±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±75 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2)	: DB package 70°C/W
	DGV package 92°C/W
	DW package 58°C/W
	N package 69°C/W
	PW package 83°C/W
Storage temperature range, T <sub>sto</sub>	

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The package thermal impedance is calculated in accordance with JESD 51.



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### recommended operating conditions (see Note 3)

		SN54AHCT373		SN74AHCT373		UNIT
		MIN	MAX	MIN	MAX	UNII
VCC	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V <sub>IL</sub>	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	5.5	0	5.5	V
٧o	Output voltage	0	VCC	0	Vcc	V
ІОН	High-level output current		-8		-8	mA
l <sub>OL</sub>	Low-level output current		8		8	mA
Δt/Δν	Input transition rise or fall rate		20		20	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T,	ղ = 25°C	;	SN54AH	CT373	SN74AH	UNIT	
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vari	I <sub>OH</sub> = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
VOH	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		3.8		V
Voi	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	<u> </u>
VOL	$I_{OL} = 8 \text{ mA}$	4.5 V			0.36		0.44		0.44	V
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.25		±2.5		±2.5	μΑ
lį	$V_I = V_{CC}$ or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40		40	μΑ
Δl <sub>CC</sub> †	One input at 3.4 V, Other inputs at V <sub>CC</sub> or GND	5.5 V			1.35		1.5		1.5	mA
C <sub>i</sub>	$V_I = V_{CC}$ or GND	5 V		4	10				10	pF
Co	$V_O = V_{CC}$ or GND	5 V		9						pF

 $<sup>^{*}</sup>$  On products compliant to MIL-PRF-38535, this parameter is not production tested at  $V_{CC} = 0 \text{ V}$ .

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		T <sub>A</sub> = 25°C SN54AHCT3		SN74AHCT373		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, LE high	6.5		6.5		6.5		ns
t <sub>su</sub>	Setup time, data before $\overline{LE} \downarrow$	1.5		1.5		1.5		ns
t <sub>h</sub>	Hold time, data after LE↓	3.5		3.5		3.5		ns



<sup>†</sup> This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or VCC.

### SN54AHCT373, SN74AHCT373 **OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS**

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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	T <sub>A</sub> = 25°C		SN54AH	ICT373	SN74AH	CT373	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	D	Q	C <sub>I</sub> = 15 pF		5.1*	8.5*	1*	9.5*	1	9.5	ns
tPHL		ų ,	CL = 13 pr		5.1*	8.5*	1*	9.5*	1	9.5	115
t <sub>PLH</sub>	LE	Q	C <sub>L</sub> = 15 pF		7.7*	12.3*	1*	13.5*	1	13.5	ns
t <sub>PHL</sub>	LE	Q	CL = 15 pr		7.7*	12.3*	1*	13.5*	1	13.5	115
<sup>t</sup> PZH	<del></del>	Q	C 15 pE		6.3*	10.9*	1*	12.5*	1	12.5	ns
tPZL	ŌĒ	Q	C <sub>L</sub> = 15 pF		6.3*	10.9*	1*	12.5*	1	12.5	115
t <sub>PHZ</sub>	ŌĒ	Q	C <sub>I</sub> = 15 pF		6*	10.2*	1*	11*	1	11	ns
t <sub>PLZ</sub>			CL = 13 pr		6*	10.2*	1*	11*	1	11	115
<sup>t</sup> PLH	D	Q	C: - 50 pF		5.9	9.5	1	10.5	1	10.5	ns
t <sub>PHL</sub>		Q	C <sub>L</sub> = 50 pF		5.9	9.5	1	10.5	1	10.5	115
<sup>t</sup> PLH	LE	Q	C <sub>L</sub> = 50 pF		8.5	13.3	1	14.5	1	14.5	ns
t <sub>PHL</sub>	LL	Q	CL = 30 pr		8.5	13.3	1	14.5	1	14.5	115
<sup>t</sup> PZH	ŌĒ	Q	C <sub>I</sub> = 50 pF		7.1	11.9	1	13.5	1	13.5	ns
t <sub>PZL</sub>	OE .	ų ,	CL = 30 pr		7.1	11.9	1	13.5	1	13.5	115
<sup>t</sup> PHZ	<del></del>	Q	C <sub>L</sub> = 50 pF		6.8	11.2	1	12	1	12	ns
t <sub>PLZ</sub>	ŌĒ	, , , , , , , , , , , , , , , , , , ,	GL = 50 pr		6.8	11.2	1	12	1	12	115
t <sub>sk(o)</sub>			C <sub>L</sub> = 50 pF			1**				1	ns

<sup>\*</sup> On products compliant to MIL-PRF-38535, this parameter is not production tested.

## noise characteristics, $V_{CC} = 5 \text{ V}$ , $C_L = 50 \text{ pF}$ , $T_A = 25^{\circ}\text{C}$ (see Note 4)

	PARAMETER		SN74AHCT373		
	PARAMETER		MAX	UNIT	
VOL(P)	Quiet output, maximum dynamic V <sub>OL</sub>		0.8	1.2	V
V <sub>OL</sub> (V)	Quiet output, minimum dynamic V <sub>OL</sub>		-0.8	-1.2	V
V <sub>OH(V)</sub>	Quiet output, minimum dynamic V <sub>OH</sub>	4.1			V
V <sub>IH(D)</sub>	High-level dynamic input voltage	2			V
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.8	V

NOTE 4: Characteristics are for surface-mount packages only.

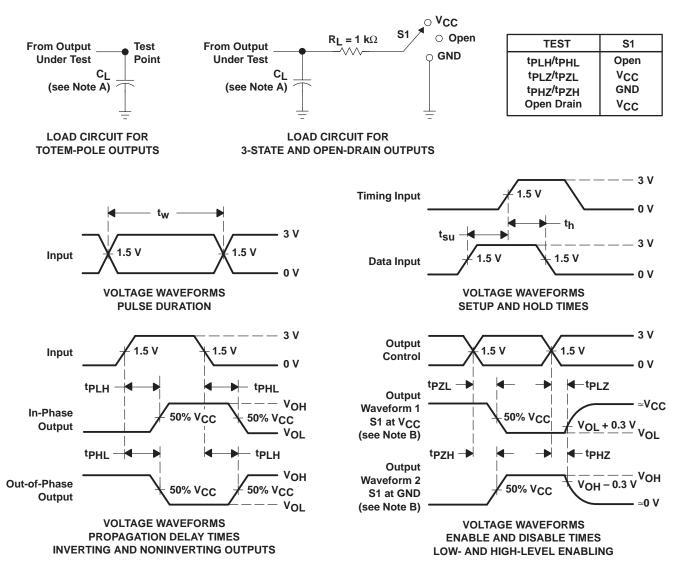
## operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

ĺ		PARAMETER	TEST C	ONDITIONS	TYP	UNIT
Ī	C <sub>pd</sub>	Power dissipation capacitance	No load,	f = 1 MHz	17	pF



<sup>\*\*</sup> On products compliant to MIL-PRF-38535, this parameter does not apply.

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f \leq 3 \ ns$ ,  $t_f \leq 3 \ ns$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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